



## Description

### JMG N-channel Enhancement Mode Power MOSFET

#### Features

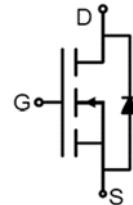
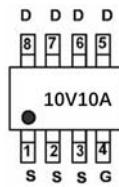
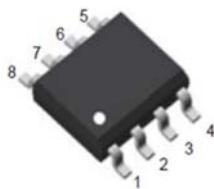
- 100V,7A
- $R_{DS(ON)} < 140\text{m}\Omega$  @  $V_{GS} = 10\text{V}$
- $R_{DS(ON)} < 300\text{m}\Omega$  @  $V_{GS} = 4.5\text{V}$
- Advanced Split Gate Trench Technology
- Excellent  $R_{DS(ON)}$  and Low Gate Charge
- Lead free product is acquired

#### Application

- Load Switch
- PWM Application
- Power management



100% UIS TESTED!  
100%  $\Delta V_{ds}$  TESTED!



SOP-8 top view

Marking and pin Assignment

Schematic Diagram

## Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
10V10A	JMGP10V10A	TAPING	SOP-8	13inch	4000	48000

## Absolute Maximum Ratings ( $T_c = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter		Max.	Units
$V_{DSS}$	Drain-Source Voltage		100	V
$V_{GSS}$	Gate-Source Voltage		$\pm 20$	V
$I_D$	Continuous Drain Current		7	A
	$T_c = 100^\circ\text{C}$	4.5	A	
$I_{DM}$	Pulsed Drain Current <sup>note1</sup>		28	A
$E_{AS}$	Single Pulsed Avalanche Energy <sup>note2</sup>		2.25	mJ
$P_D$	Power Dissipation	$T_c = 25^\circ\text{C}$	13.7	W
$R_{eJC}$	Thermal Resistance, Junction to Case		9.1	$^\circ\text{C}/\text{W}$
$T_J, T_{STG}$	Operating and Storage Temperature Range		-55 to +150	$^\circ\text{C}$

**Electrical Characteristics** ( $T_J=25^\circ\text{C}$  unless otherwise specified)

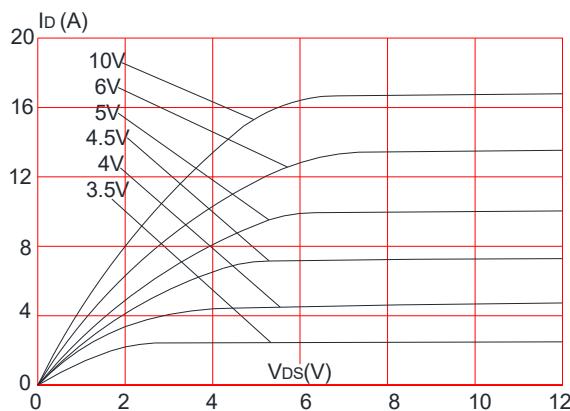
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristic</b>						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	100	-	-	V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=100\text{V}, V_{GS}=0\text{V}$ ,	-	-	1.0	$\mu\text{A}$
$I_{GSS}$	Gate to Body Leakage Current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.5	-	2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS}=10\text{V}, I_D=3.5\text{A}$	-	110	140	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=2\text{A}$	-	160	300	
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS}=25\text{V}, V_{GS}=0\text{V}, f=1\text{MHz}$	-	206	-	pF
$C_{oss}$	Output Capacitance		-	29	-	pF
$C_{rss}$	Reverse Transfer Capacitance		-	1.4	-	pF
$Q_g$	Total Gate Charge	$V_{DS}=25\text{V}, I_D=5\text{A}, V_{GS}=10\text{V}$	-	4.3	-	nC
$Q_{gs}$	Gate-Source Charge		-	1.5	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	1.1	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-on Delay Time	$V_{DS}=25\text{V}, I_D=5\text{A}, R_{\text{GEN}}=2\Omega, V_{GS}=10\text{V}$	-	14.7	-	ns
$t_r$	Turn-on Rise Time		-	3.5	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	20.9	-	ns
$t_f$	Turn-off Fall Time		-	2.7	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_s$	Maximum Continuous Drain to Source Diode Forward Current	-	-	7	A	
$I_{sM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	28	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}, I_s=7\text{A}$	-	-	1.2	V
$trr$	Body Diode Reverse Recovery Time	$I_F=5\text{A}, dI/dt=100\text{A}/\mu\text{s}$	-	32	-	ns
$Qrr$	Body Diode Reverse Recovery Charge		-	39	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

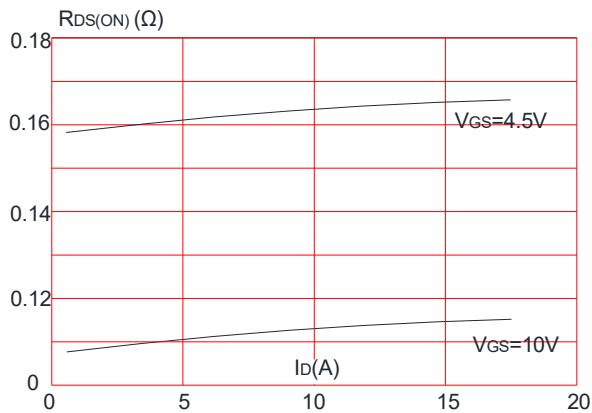
2. EAS condition:  $T_J=25^\circ\text{C}, VDD=50\text{V}, VG=10\text{V}, RG=50\Omega, L=0.5\text{mH}, IAS=3\text{A}$ 3. Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 0.5\%$

## Typical Performance Characteristics

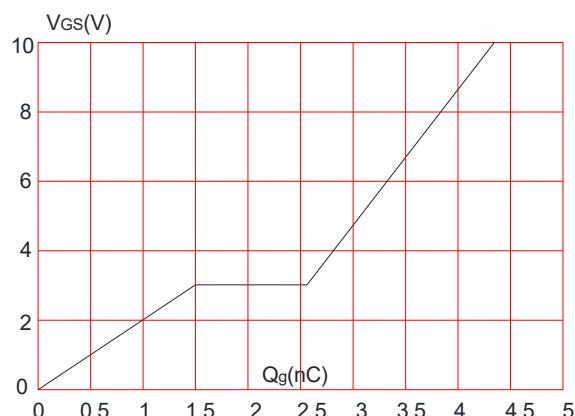
**Figure 1:** Output Characteristics



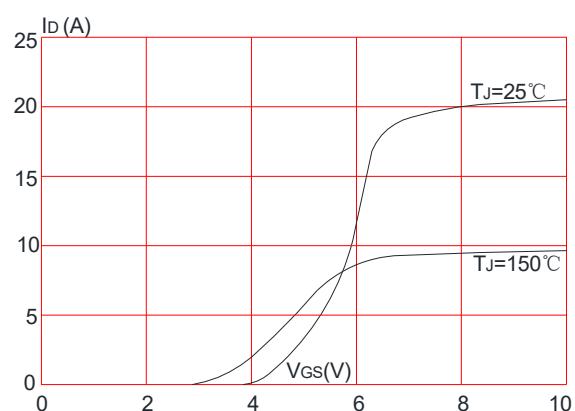
**Figure 3:** On-resistance vs. Drain Current



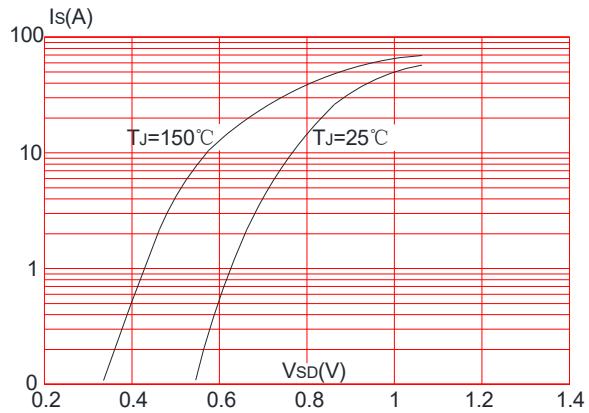
**Figure 5: Gate Charge Characteristics**



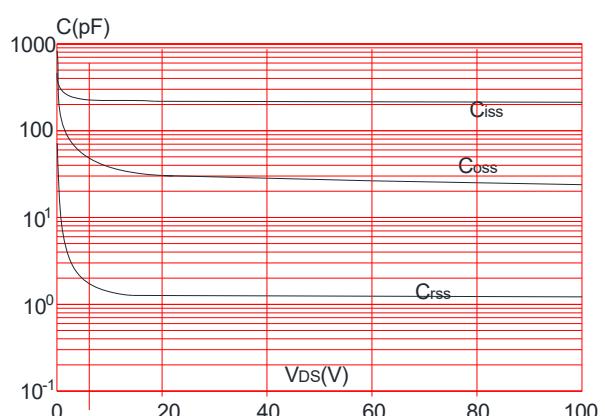
**Figure 2:** Typical Transfer Characteristics



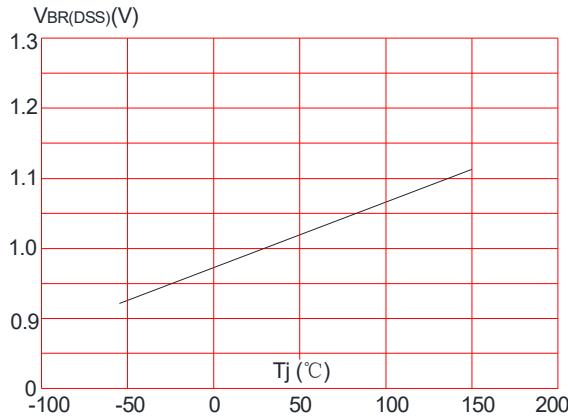
**Figure 4:** Body Diode Characteristics



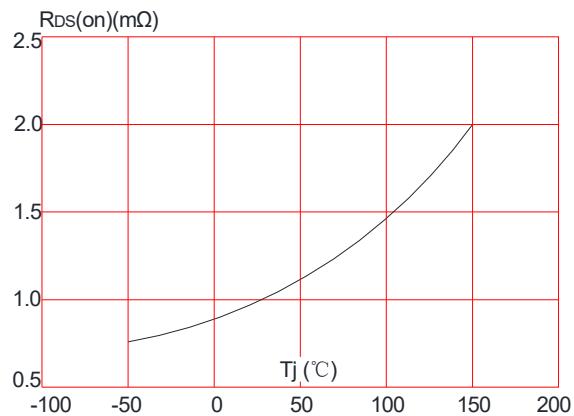
**Figure 6: Capacitance Characteristics**



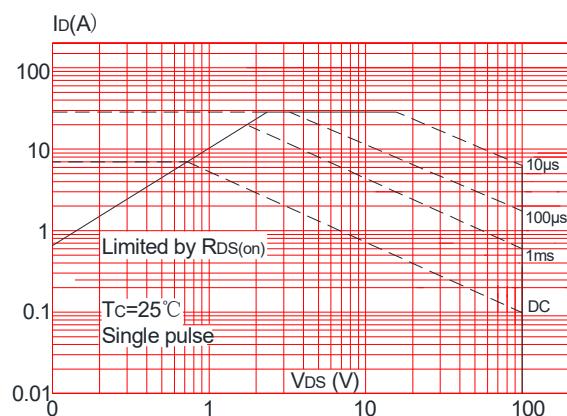
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



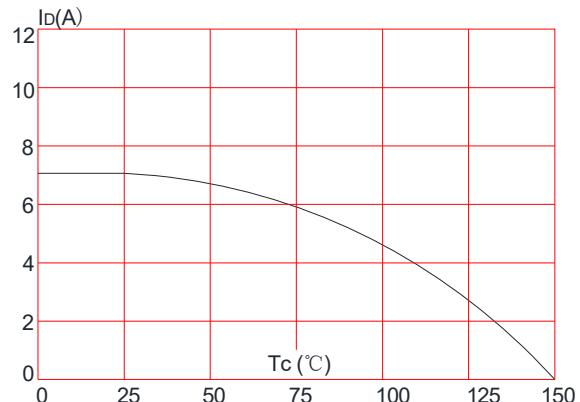
**Figure 8:** Normalized on Resistance vs. Junction Temperature



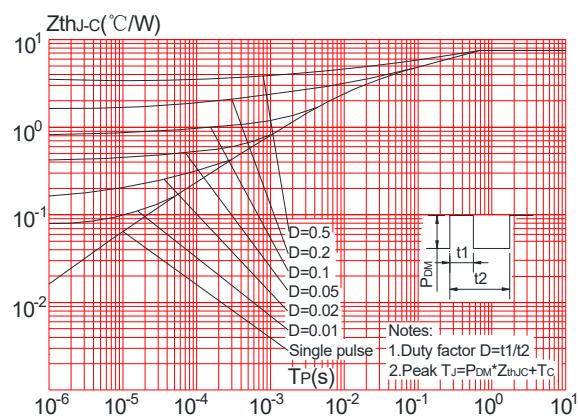
**Figure 9:** Maximum Safe Operating Area



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature



**Figure 11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



## Test Circuit

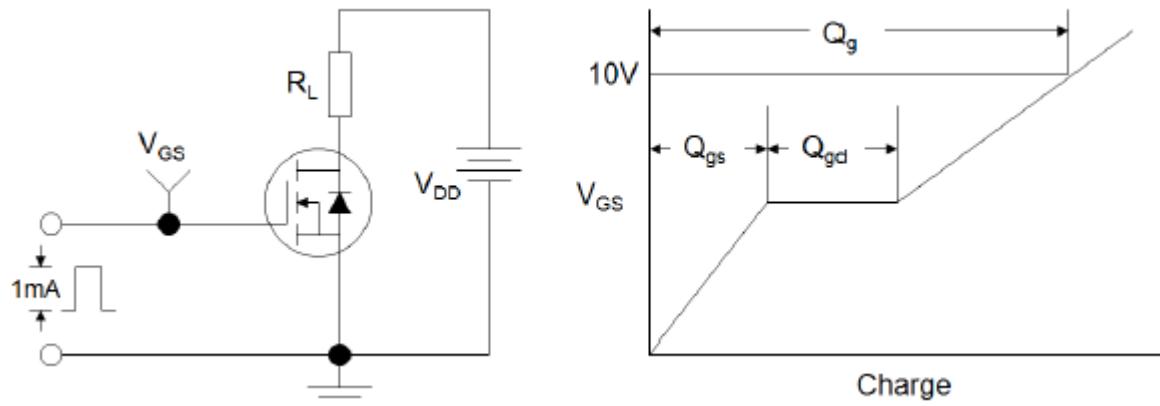


Figure1:Gate Charge Test Circuit & Waveform

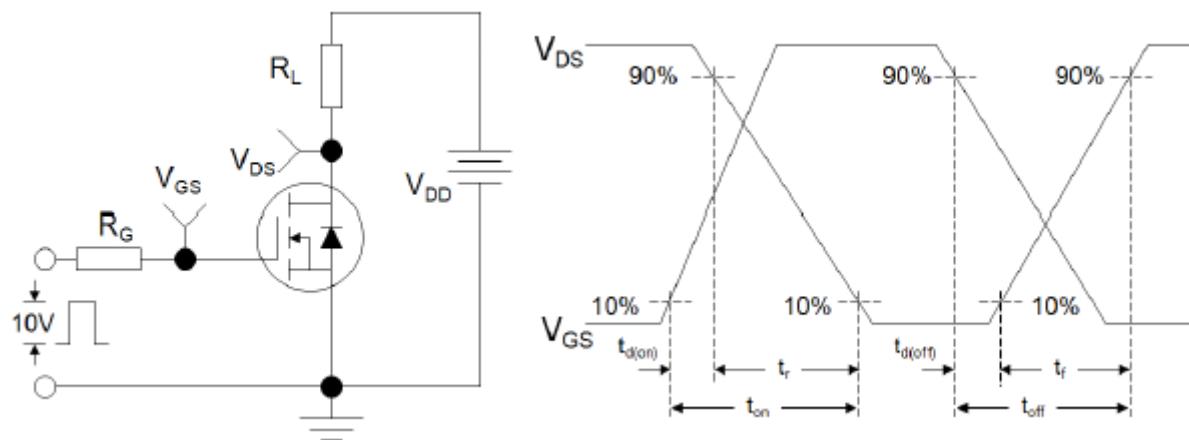


Figure 2: Resistive Switching Test Circuit & Waveforms

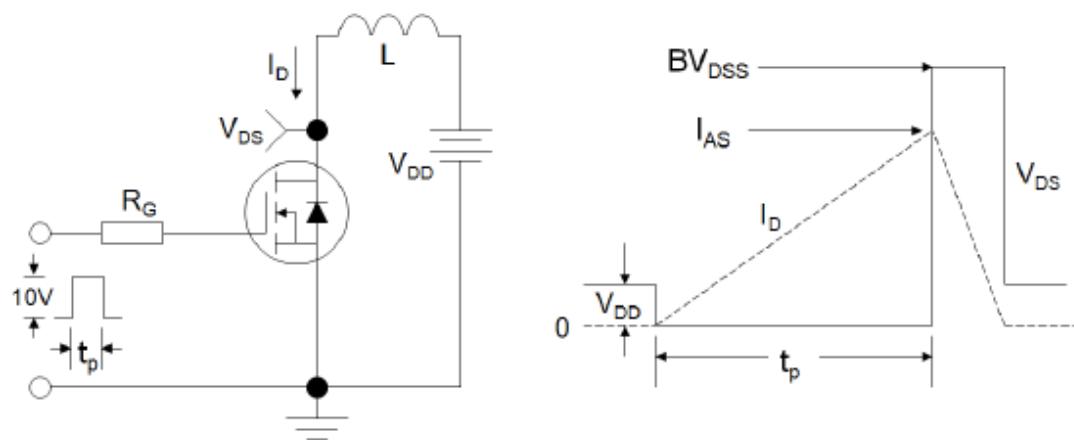
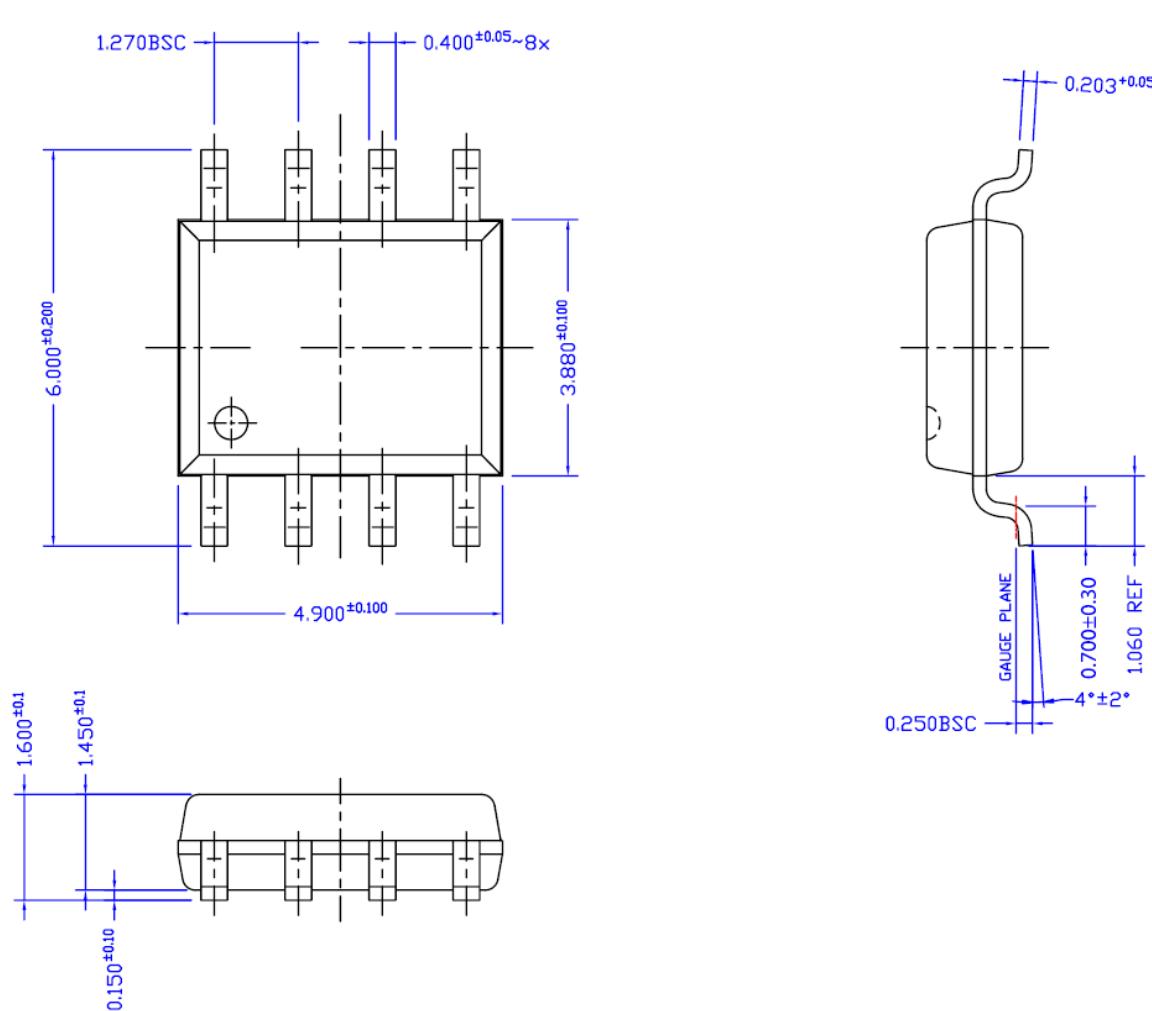


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

## Package Mechanical Data-SOP-8



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